

Search Notes

Application/Control No.

10/532,213

Examiner

Jinhee J. Lee

Applicant(s)/Patent under
Reexamination

FAHEY, MARK T

Art Unit

2831

SEARCHED

Class	Subclass	Date	Examiner
174	72A	7/27/2006	LEE
439	all (text	}}	/)

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
174	as above	7/27/2006	LEE
439	as above	/	/

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Sea text search attached	7/27/2006	LEE